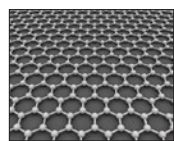


ProductNews

NEW PELCO® Graphene TEM Support Films



Ted Pella, Inc. announced the availability of the new research-ready PELCO® graphene TEM support films. These unique films are supported by lacey carbon film on a 300-mesh copper grid. The single, continuous graphene sheet covers the entire 300-mesh area of the TEM grid with a total usable area of 75%. It is available as 2-layer graphene for UHR imaging or 3–5 layer robust graphene as a nano-scale experimental platform.

Ted Pella, Inc.
www.tedpella.com

Aven HD Color Camera Offers High-Level Features for Microscopy



Image settings are adjusted without a computer connection, as the camera has a HDMI port for a direct link to a monitor. A built-in SD card and snapshot controller let users save images easily. The HD Color Camera, which comes with a C-mount for coupling to standard microscopes, has a CMOS 1/3" sensor broadcasting video in 1080P at 60 frames per second. White balance and exposure can be automatic or adjusted manually.

Aven, Inc.
www.aventools.com/sales-info.html

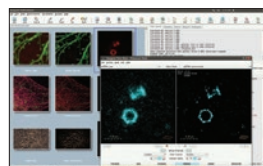
Prior Scientific Introduces the HF108IX3 Filter Wheel Deck for Olympus IX3 Microscopes



Simple cassette-like insertion into the side deck of the Olympus IX3 makes installation quick and easy. The HF108IX3 provides a compact high-speed filter wheel option that accommodates up to eight 32 mm diameter filters. The unit is mounted below the nosepiece, which enables the user to switch between wavelengths at high speed but also see the fluorescent images through the eyepieces of the IX3 microscope and the camera.

Prior Scientific, Inc.
www.prior.com

Huygens STED deconvolution



Scientific Volume Imaging offers STED deconvolution within the new Huygens 4.3 version, to push the microscopic super-resolution limits set by the Leica Microsystems STED microscopes. Huygens STED deconvolution offers a huge increase in contrast and a 2× improvement in high lateral STED resolution. STED z-resolution is now on the level of confocal Z-resolution with reduced noise, depth-dependent spherical aberration, and drift correction. STED image and deconvolution parameters can be automatically extracted from bead images.

Scientific Volume Imaging, bv
www.svi.nl

New SPOT Insight™ Gigabit Camera



The new high-speed SPOT Insight Gigabit Camera, with 4 MP resolution and a very large field of view, is designed for remarkable quality images and uses a Kodak 21.4 mm scientific CCD sensor. Fixed images can be captured in all common formats for easy addition to tumor board presentations or journal submissions. Low-noise circuitry enables 14 frames per second live imaging with incredible clarity that captures attention.

SPOT Imaging Solutions Corporation
www.spotimaging.com

Digital HD Microscope Cameras from Leica Microsystems



The new high-performance cameras provide high-speed, precise images in real time at a rate of up to 30 frames per second. They are directly connectable to an HD monitor as a stand-alone solution or to a computer via USB interface. Although the 2.5-megapixel Leica MC120 HD is ideal for almost all microscopic applications, the Leica MC170 HD with a resolution of 5 megapixels is especially well suited for acquiring the finest details at low magnifications.

Leica Microsystems GmbH
www.leica-microsystems.com

AirClean Systems Launches New Patriot Ductless Fume Hoods



Patriot ductless fume hoods feature the easy-to-use AirSafe™ NXT automatic safety controller for added operator safety. This color touchscreen controller automatically increases or decreases blower speed to maintain the user's pre-set face velocity, ensuring airflow is within standard operating parameters. The current face velocity is displayed at all times. AirSafe NXT also monitors the bonded carbon filtration bed, alerting the user audibly and visually should filter saturation occur.

AirClean Systems
www.aircleansystems.com/ductless-fume-hoods/patriot

B&W Tek Announces Enhanced NanoRam Handheld Raman Spectrometer



B&W Tek, Inc. announced major enhancements to their NanoRam handheld Raman spectrometer. The next generation of NanoRam offerings include an embedded 2D barcode scanner, batch scanning capabilities, IP-64 rated (dust-tight and splash-proof) housing, Ethernet connectivity, and software enhancements to better facilitate tracking and reporting. Also introduced are two new sampling accessories, a 12-inch immersion shaft for sampling out of large drums, and a tablet holder to easily measure finished products.

B&W Tek, Inc.
www.bwtek.com

Bruker Introduces a New AFM Semiconductor Characterization Solution



Bruker announced the release of the Dimension Icon[®] SSRM-HR, a new atomic-force microscope configuration including the Scanning Spreading Resistance Microscopy (SSRM) module, designed specifically for high-resolution semiconductor characterization. Integrating Bruker's industry-leading Dimension Icon AFM platform with an environmental control system capable of 1 ppm gas purity and high-vacuum control, the Dimension Icon SSRM-HR system provides improved repeatability and spatial resolution in semiconductor carrier profiling. Buried gate oxide layers as thin as 5 Å are detected routinely.

Bruker Corporation
www.bruker.com

The New Reliable, Two-Stage DuoLine Rotary Vane Pumps



Pfeiffer Vacuum introduced the new two-stage DuoLine rotary vane pumps. The compact vacuum pumps are distinguished by a newly developed pump system and optimized cooling. These changes have a significant impact on the service lives of the pumps. The long maintenance intervals, the energy-efficient motors, and the optional oil return lower the operating costs to a very low level. The operating costs of the magnetically coupled pump are very low, as it is virtually maintenance-free.

Pfeiffer Vacuum, inc.
www.pfeiffer-vacuum.com

Prior Scientific Introduces the LumaSpec 800 Compact Microscope Illumination Spectrometer



A new ultra-compact spectrometer for microscopy applications, the LumaSpec 800 provides quantitative spectral data for virtually any microscopy light source. Using an illumination target in a 3" × 1" glass slide format, the LumaSpec 800 is able to check microscope illumination at the sample plane, where it matters most. The LumaSpec 800 provides quantitative and graphical information from 350 nm to 800 nm with 1.5 nm resolution, to quantifying your illumination system.

Prior Scientific, Inc.
www.prior.com

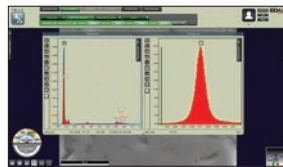
UV-Visible-NIR, Fluorescence, and Raman Microspectroscopy with the New 20/30 PV[™] from CRAIC Technologies



CRAIC Technologies is proud to introduce the 20/30 PV[™] microspectrophotometer. As the new flagship product for CRAIC Technologies, the 20/30 PV[™] microspectrophotometer is designed to non-destructively analyze many types of microscopic samples from the deep ultraviolet to the near infrared by several different techniques. Analysis of samples can be done by absorbance, reflectance, Raman, luminescence, and fluorescence with unparalleled speed and accuracy and all with the same instrument.

CRAIC Technologies, inc.
www.microspectra.com

WDS Joins the Team: EDAX Launches Team[™] WDS Analysis System



With the introduction of TEAM[™] WDS, EDAX has merged its Wavelength Dispersive Spectrometry (WDS) product line into the highly successful TEAM[™] Analysis System, which improves workflow and streamlines all three microanalysis techniques—energy dispersive spectroscopy (EDS), electron backscatter diffraction (EBSD), and WDS—into one common user interface. TEAM[™] WDS also introduces Smart Focus, a fully automated focusing routine that provides complete microscope optimization for WDS analysis.

EDAX is a unit of AMETEK Materials Analysis Division
www.edax.com

Piezo-Sample Scanners and Fast Objective Focusing Devices



PI offers two basic solutions for focusing and 3D imaging: positioners that move the lens and sample positioners. PIFOC[®] piezo-driven lens positioners provide fast focus control for autofocus applications and can also be used in 3D imaging/Z-stack image acquisition due to their rapid, millisecond-range settling speed. Several devices are available to match different objective sizes and weights. Travel ranges from 50 µm to 2 mm are available.

PI (Physik Instrumente) LP
www.microscopestage.net

New Materials Microscope for Routine Inspection and Quality Control



The new materials microscope Leica DM2700 M from Leica Microsystems is ideal for all kinds of routine inspection tasks in metallography, earth science, forensic investigation, and materials quality control and research. It offers users state-of-the-art universal white-light LED illumination with high-quality Leica optics. The ultra-bright, high-power LED illumination provides users with a constant color temperature of 4500 K for brightfield, darkfield, interference contrast, and polarized light methods plus built-in oblique illumination technology.

Leica Microsystems GmbH
www.leica-microsystems.com

FEI Launches New ASPEX CleanCHK Analyzer for Automotive Manufacturing



FEI Company announced the new ASPEX CleanCHK[™] analyzer—the first fully automated, electron beam-based particulate contamination monitor specifically designed for automotive applications. The CleanCHK system allows automotive parts manufacturers to improve production line performance and reduce warranty costs. The system is easy to use and can be installed on the production floor. CleanCHK is a fully integrated solution that combines a scanning electron microscope (SEM) for high-resolution imaging and an X-ray spectrometer to determine elemental composition.

FEI Company
www.fei.com